

<b>Notice of References Cited</b>	Application/Control No. 09/806,417	Applicant(s)/Patent Under Reexamination SEKIDO ET AL.	
	Examiner Stefan Staicovici	Art Unit 1732	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5746955 ✓	05-1998	Calapp et al.	264/103
	B	US-6159414 ✓	12-2000	Tunis, III et al.	264/510
	C	US-5169590 ✓	12-1992	Johnson et al.	264/506
	D	US-5985197 ✓	11-1999	Nelson et al.	264/221
	E	US-5080850 ✓	01-1992	Holloway	264/258
	F	US-4780262 ✓	10-1988	Von Volkli	264/512
	G	US-5961764 ✓	10-1999	Sydow et al.	156/242
	H	US-5939013 ✓	08-1999	Han et al.	264/510
	I	US-5601852	02-1997	Seemann	425/112
	J	US-5853651 ✓	12-1998	Lindsay et al.	264/512
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 98/32589	07-1998	WIPO	Lunde et al.	
	O	WO 98/30374	07-1998	WIPO	Lopez et al	
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.